

Notice of References Cited	Application/Control No. 10/064,690	Applicant(s)/Patent Under Reexamination BENNIE ET AL.	
	Examiner Phung T Nguyen	Art Unit 2632	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,522,960	02-2003	Nada, Mitsuhiro	701/22
	B	US-			
	C	US-			
	D	US-			
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	F	US-			
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FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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